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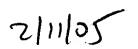
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U.S.L. artment of Commerce Form PTO-1449 Atty Docket 0756-2131 Serial No. 09/535,015 (Rev. 8-83) Patent and Trademark Office Applicants: Shupei YAMAZAKI et al. INFORMATION DISCLOSURE STATEMENT Group Art Unit: 2825 Filing Date: March 24, 2000 FOREIGN PATENT DOCUMENTS Class Subclass Translation Country **Document Number** Examiner Yes Initial Abst. 08-129360 -05/21/1996 5W( Japan Abst. 09/13/1996 Japan 08-234683 Abst. 09/17/1996 08-241047 Japan Abst. 09/17/1996 Japan 08-241048 Abst. 09/17/1996 Japan 08-241057 Abst. 09/17/1996 08-241997 Japan Full 06/10/1985 Japan 60-105216 Full 04/01/1986 Japan 61-063017 Abst. 04/01/1986 Japan 61-063107 Abst. 07/25/1987 Japan 62-169356 Abst. 03/27/1989 Japan 64-081324 OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Examiner Initial Caune et al., "Combined CW Laser and Furnace Annealing of Amorphous Si and Ge in Contact With Some Metals", January 1, 1989, pp. 597-604, Applied Surface Schience, Vol. 36 Stoemnos et al., "Crystallization of Amorphous Silicon By Reconstructive Transformation Utilizing Gold", March 18, 1991, pp. 1196-1198, Appl. Phys. Lett. 58(11) Kakkad et al., "Crystallized Si-Films By Low-Temperature Rapid Thermal Annealing of Amorphous Silicon", March 1, 1989, pp. 2069-2072, J. Appl. Phys. 65(5) Oki et al., "Effect of Deposited Metals On the Crystallization Temperature of Amorphous Germanium Film", 1969, pp. 1056, Jpn. J. Appl. Phys. 8 Kuznetsov et al., "Enhanced Solid Phase Epitaxial Recrystallization of Amorphous Silicon Due to Nickel Silicide Precipitation Resulting From Ion Implantation and Annealing", 1993, pp. 990-993, Nucl. Instruments Methods Physics Research, 880/881 Takenaka et al., "High Mobility Poly-Si Thin Film Transistors Using Solid Phase Crystallized a-Si Films Deposited by Plasma Enhanced Chemical Vapor Deposition", December 1990, pp. L2380-L2383, Jpn. J. Appl. Phys. Vol. 29, No. 12 Hatalis et al., "High Performance Thin-Film Transistors in Low Temperature Crystallized LPCVD Amorphous Silicon Films", August 1987, pp. 361-364, Elec. Dev. Letters Vol. EDL 8, No. 8 Zorabedian et al., "Lateral Seeding of Silicon-on-Insulator Using an Ellipitical Laser Beam: A Comparison of Scanning Methods", 1984, pp. 81-86, Mat. Res. Soc. Symp. Proc. Vol. 33 Spaepen et al., "Metal-Enhanced Growth of Silicon", 1992, pp. 483-499, Crucial Issues in Semiconductor Materials & Processing Technologies Green et al., "Method To Purify Semiconductor Wafers", October 1973, pp. 1612-1613, IBM Tech. Discl. Bulletin Vol. 16, SUC **LUPY** Date Considered Examiner \*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this formwith next communication to applicant.

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STATEMENT BY APPLICANT

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Filing Date	March 24, 2000					
First Named Inventor	Shunpei YAMAZAKI et al.					
Group Art Unit	2811					
Examiner Name	S. Crane					
Attorney Docket Number	0756-2131					

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				Examiner Name	S. Crane			
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SWC	5,728,259	03/17/1998	Suzawa et al.				

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10/18/02

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this formwith next communication to applicant.

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Form PTO-1 (Rev. 8-83)	449	Department of Commerce lentend rademark Office	Atty Docket 0756-		Serial No. 09	/535,015
IN	FORMATION DISCLOSU		Applicants: Shupei YAM	IAZAKI et a	ıl.	
PAR		SEP 0 5 2001	Filing Date: March 24, 2000		Group Art Unit: 2825	
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Sw(	07-335900	12/22/1995	JP			Eng Abst
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Form F20-1449 U.S. Department of Commerce (Rev. 8-83) Patent and Trademark Office			Attorney Docket No. 0756-2131		Serial No. Not Yet Assigned			
INFORMATION DISCLOSURE STATEMENT			Applicant: Shunpei YAMAZAKI et al.			015 00 00		
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Sheet 2 of 3

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Attorney Docket No. 0756-2131

Applicant: Shunpei YAMAZAKI et al.

Serial No. Not Yet Assigned

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(Use several sheets if necessary)

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